

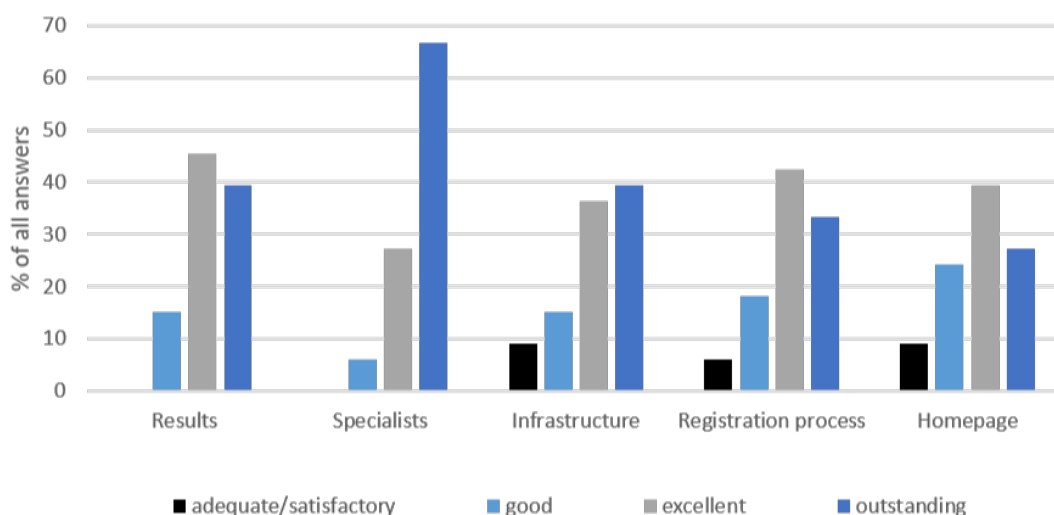
NANO IMAGING LAB

Newsletter

May 17th, 2021

Dear Nano Imaging Lab user

As a service facility, we always strive to offer our customers the best possible service and a variety of surface analysis and microscopy techniques. At the beginning of this year, we conducted an anonymous survey among all users of the NI Lab in order to find out about customer satisfaction and needs. We were very pleased that over 30 people responded. At this point, a big thank you to everyone who took part in the survey!



We received consistently positive feedback regarding the scientific results obtained, the technical skills / competencies of the specialists, the technical infrastructure of the laboratory, the convenience of the registration process and the information content on our website.

SERVICE IN GENERAL



Although the survey turned out to be extremely satisfactory, we also received individual comments that we are gladly implementing as suggestions for improvement. This applies in particular to better publicizing and demonstrating our multitude of applications and methods, be it with an adapted website or with additional video and image material. A workshop for customers with specific questions and requirements is also being planned.

Please find **all our provided microscopy services** on our website www.nanoimaging.unibas.ch and in the following list:

- **SEM (Scanning Electron Microscopy)**
 - Low and High Resolution Imaging (SE- and BSE detector)
 - Energy Dispersive X-Ray Microanalysis EDX
 - Cryo Scanning Electron Microscopy

- **FIB (Focused Ion Beam)**
 - Imaging (SE-, BSE- and STEM detector)
 - Energy Dispersive X-Ray Microanalysis (EDX)
 - TEM lift out and TEM lamella
 - Nanofabrication and micromanipulation
 - Gas injection system for Pt-, W-, C-, Co- and H₂O- deposition
 - Correlative Microscopy (LM – SEM)

- **TEM (Transmission Electron Microscopy) with negative stain**

- **AFM (Atomic Force Microscopy)**
 - Standard imaging modes (Contact and Dynamic Modes)
 - Lateral Force Mode
 - Phase Imaging Mode
 - Magnetic Force Microscopy (MFM)
 - Conductive AFM (CAFM)
 - Piezoresponse Force Microscopy (PFM)
 - Electrostatic Force Microscopy (EFM)
 - Kelvin Probe Force Microscopy (KPFM)
 - Force Spectroscopy (indentation, unfolding and stretching)
 - Force Modulation
 - QI Mode (Quantitative Imaging) with Adhesion, Stiffness and Youngs Modulus
 - Force Mapping
 - Lithography and Nanomanipulation

- **LSM (reflection-type 3D Laser Scanning Microscopy)**

- **CLSM (Fluorescence Confocal Laser Scanning Microscopy)** operated at the Imaging Core Facility of the Biozentrum

COMING SOON!

- **TEM/STEM** with EDX detector (**Scanning Transmission Electron Microscopy**) at the Nano Imaging Lab
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Are you looking for other methods that are not explicitly mentioned here?
Please don't hesitate to contact us. We are happy to help you finding the
respective specialists within our large scientific network.

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